Panasonic

Ultrahigh High Accurate 3-D Profilometer General Catalog



▲ Safety Precautions

Be sure to read the instruction manual carefully before using the product.

inquiries

•In order to ensure the safe use of the products listed in the catalog, we ask that you thoroughly check the instruction manual attached to the equipment and the warnings of the equipment before carrying out proper operations, regardless of whether the equipment is in operation or not.

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https://www.panasonic.com/global/business/ua3p/

Panasonic Production Engineering Co., Ltd.

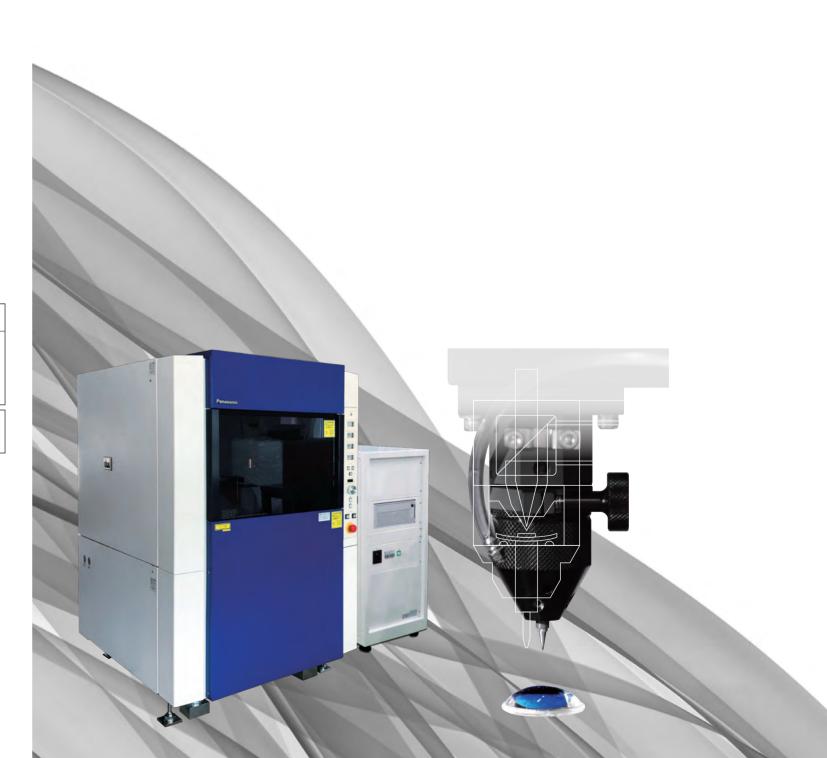
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- The rating and design of the product are subject to change without notice for the purpose of improvement.
 This product is designed for use in Japan. Consult your dealer for overseas use.
 Be sure to read the instruction manual carefully before using the product.





"No measurement, No production."

This slogan was born during difficult challenges that Panasonic was facing.

UA3P has been used by customers around the world since its launching and has now gained their trust as the primary standard in the optical industry.

For example, lenses are produced through the processes of creating molds with a processing machine and using a molding machine to form lens products.

In order to control production conditions that is changing constantly, measuring equipment with higher precision that enables us to capture "changes" is indispensable. We believe that high-quality manufacturing can only be achieved with high-precision measuring equipment.

The world's highest-level 3-D profilometer "UA3P"

In the years ahead, its nanometer-level reproducibility will contribute to the realization of the dreams not only in the optical industry but in the wide range of customers in "Measurement" Evolving UA3P is our mission to society.

Features of UA3P

Absolute surface profiling through contact measurement

- Rotationally symmetric aspheric surface (pancake, gull-wing, etc.)

Free-form surface(polynomial, biconic, anamorphic, etc.)

Achieving various analyses based on measurement data

Optimized radius calculation (Best FitR) / Zernike analysis / frequency analysis, etc

Enabling surface roughness measurement even for objects with complex shapes

CAD data-based evaluation Convert CAD to Point Cloud for Evaluation

(PARASOLID, STEP, IGS)

Ultra-high precision measurement Achieving single nanometer level reproducibility

Flexible NC paths capable of measuring

Evaluatable Decenter front and back/ Decenter respect outline

> **Enabling measurement and evaluation** without design formulas

Work leveling and labor saving through automatic measurement

Technology for ultra-precise measurement

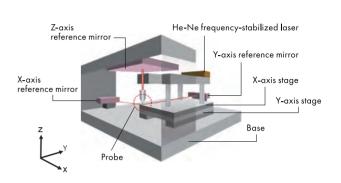
UA3P which is supporting evolution of optical components, as the primary standard in the optical industry.

He-Ne laser length measurement technology has realized absolute coordinates in nano precision.

Coordinate measurement technology

The coordinate system of the instrument consists of 3 reference planes (mirrors) independent of the stage, and each XYZ axis is measured with 0.3 nm resolution by laser interferometry using a frequency stabilized He-Ne laser as a light source. These technology suppresses the influence of the squareness and straightness of the stage, and achieves high-precision measurement.

Measurement error due to 0.05 µm max. (up to 100 mm) coordinate axes 0.3 µm max. (up to 500 mm)



Measuring probes -



Top surface measurement probe / AFP



High precision scanning measurement is possible with ultra-low measuring force on an object.

Stylus is held by micro-air slider, and focusing laser detects movement of the stylus and follows AFP position to the shape of the object with kept measuring force is constant.



Side surface measurement probe / S-AFP



The tilt of a probe mirror detected with high precision is fed back to the XY stages to enable scanning measurement with low contact force



Enabling to measure pastic product such as a lens holder (barrel), without deforming.

- Measuring force : 0.3 mN (30 mgf) • Measurement accuracy : $\pm 0.15 \, \mu m$ (on 90° inclination measurement)
- · Maximum measurement angle
- Horizontal measurement : 45° to 90° (angle relative to horizontal surface) ; Vertical measurement: 80° to 90° (angle relative to horizontal surface)

Evaluation Procedure using UA3P

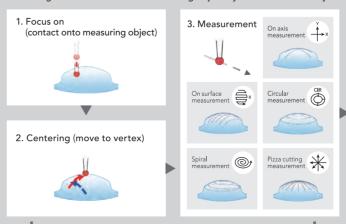
• Measuring force: 0.15 ~ 0.30 mN (15 ~ 30 mgf)

• Stylus: 30 degree tip angle, $r = 2 \mu m$ diamond stylus usable

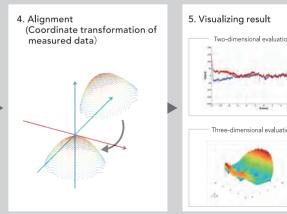
 $*0.05 \sim 0.30$ mN for UA3P - 3100 / 4000

 $0.10 \sim 0.30 \, \text{mN}$ for UA3P - 5000 H

Achieving accurate measurement with simple operation. It can deal with any kinds of design equations, and accurate shape measurement is possible by correcting installation error of a measuring object by three-dimensionally.



Automatically positioning the measurement center, and measuring on the measurement object.



Quantifying the difference between the measurement data and design formula.

Small plastic lens

Continuous and automatic measurement of high-precision small lenses. Achieving leveling work and labor saving on standard work, as well as reducing work load for operator.



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Medical camera

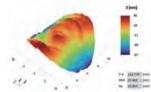
Measurement examples

Shape measurement

High-precision surface shape measurement

Detecting shape errors at the 10 nm level and contributing to mold processing correction and molding product quality control





Plastic lens / mold Lens shape evaluation

Decenter Measurement

Jig for lens decenter and tilt measurement jig

Synthesizing lens front back by using 3 balls, and evaluating decenter and tilt of optical axis at the 0.1µm level.





Decenter Measurement Jig

Multiple objects automatic measurement

Function for top-surface profilometer Function for side-surface profilometer

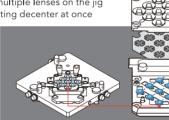
Automatic measurement function

Automatic measurement and evaluation by creating and executing an automatic program for the measurement procedure



Jig for multiple-lens decenter measurement

Installing multiple lenses on the jig and evaluating decenter at once



Medium and large size aspheric lenses and mirrors

Supported various of measurement paths and analysis methods. It can handle various processes from measurement to correction processing for photographic lenses or high-precision mirrors.



Single-lens

Measured objects

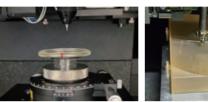


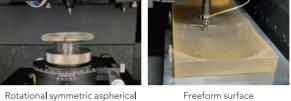
Telescope mirror

Measurement examples

Measuring path

Various measurement paths for various shapes

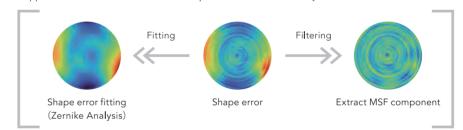




Spiral path (C) High-speed and Generating raster ring tool mark slope evaluation in unformed outline

Analysis technique

Supports evaluation and correction of shape errors with various analysis methods



Enable to output gridded data

Specifications

Туре	Standard equipment			Large-scale equipment			Twin probe(top-surface and side-surface profilometer)	ometer) High-accuracy equipment		
Model name	UA3P-300	UA3P-4	UA3P-400	UA3P-500H / 550H	UA3P-650H	UA3P-700H	UA3P-400T *2	UA3P-3100	UA3P-4000	UA3P-5000H
Appearance	Top	Top	Top	Top		Top	Top Side	Top	Top	b Top
Outer dimensions (W×D×H) mm	700×800×1510	1010×11	10×1450	1260× 1510×1580	2100×1830×2110	2100×1830×2200	1070×1230×1530	760×860×1580	1060×1200×1610	1300×1560×1900
Mass of main body	700kg (Others: 150kg)	1200kg (O	thers: 150kg)	2400kg (Others: 300kg)	8500kg (Others: 300kg)	9000kg (Others : 300kg)	750kg	900kg (Others:200kg)	1500kg (Others: 300kg)	3200kg (Others: 300kg)
Measuring range (X,Y,Z axes) mm	30×30×20	100×1	00×35	200× 200×45 UA3P-550H (+260x90x45)	400×400×120 + φ500×120	500×500×120	100×100×50	3100-A30:30×30×20 3100-A50:50×50×20	4000-A100:100×100×35 4000-A120:120×120×35	200×200×50
Measured object placement area (X,Y,Z axes) mm	100×100×120	220×22	20×132	300× 270×252.5	600×600×330	600×600×330	200×200×140	130×130×120	210×210×127.5	300×300×255
Resolution					0.3nm					
Maximum inclination angle for top-surface measurement	75°	60°	75°		75°		75°		75°	
Angle for side-surface measurement	_	_	-		_		Horizontal: 45∼90° / Vertical: 80∼90°		_	
Measurement accuracy with top-surface probe * When using the top ruby stylus or top ceramic stylus	30° or less: $\pm 0.05 \mu m$ (round trip) 45° or less: $\pm 0.08 \mu m$ (round trip) 60° or less: $\pm 0.15 \mu m$ (round trip) 70° or less: $\pm 0.15 \mu m$ (downward)	$\begin{array}{ll} 30^{\circ} \text{ or less:} \pm 0.05 \mu\text{m} \text{ (round trip)} \\ 45^{\circ} \text{ or less:} \pm 0.10 \mu\text{m} \text{ (round trip)} \\ 60^{\circ} \text{ or less:} \pm 0.30 \mu\text{m} \text{ (round trip)} \\ \end{array} \\ \begin{array}{ll} 30^{\circ} \text{ or less:} \pm 0.05 \mu\text{m} \text{ (round trip)} \\ 45^{\circ} \text{ or less:} \pm 0.08 \mu\text{m} \text{ (round trip)} \\ 60^{\circ} \text{ or less:} \pm 0.15 \mu\text{m} \text{ (round trip)} \\ 70^{\circ} \text{ or less:} \pm 0.15 \mu\text{m} \text{ (downward)} \end{array}$		30° or less: $\pm 0.05 \mu m$ (round trip) 45° or less: $\pm 0.08 \mu m$ (round trip) 60° or less: $\pm 0.10 \mu m$ (round trip) 70° or less: $\pm 0.15 \mu m$ (downward)			$\begin{array}{ll} 30^{\circ} \text{ or less:} \pm 0.04 \mu \text{m (round trip)} \\ 45^{\circ} \text{ or less:} \pm 0.05 \mu \text{m (round trip)} \\ 60^{\circ} \text{ or less:} \pm 0.06 \mu \text{m (round trip)} \\ 70^{\circ} \text{ or less:} \pm 0.08 \mu \text{m (round trip)} \\ \end{array}$		μ m (round trip) μ m (round trip) μ m (round trip)	
' '	<u> </u>				<u> </u>		70 011633. ±0.13µ111 (downward)	(Reference) Case of normal direction display (Nd) 0 \sim 70 $^{\circ}$: \pm 0.05 μ m		
Measurement accuracy by coordinate axis (XY axis measurement accuracy)	100mm or less : 0.05μ m / 200 mm or less : 0.1μ m (Repeatability within 0.05μ m)			100mm or less : 0.05 μm / 400mm or less : 0.2 μm /	200mm or less : 0.1μ m 500mm or less : 0.3μ m	(Repeatability within 0.05 μ m)	100mm or less: $0.05 \mu m$ (Repeatability within $0.05 \mu m$)			
Measurement speed	0.005~5mm/sec	0.01~10	lmm/sec	0.02~20mm/sec	0.032~	32mm/sec	Top0.01~10mm/sec, Side0.01~5mm/sec	0.005~5mm/sec	0.01~10mm/sec	0.02~20mm/sec
Operating environment Temperature / Humidity / Vibration *1	20 \sim 23 $^{\circ}$ C (Variation \pm 1 $^{\circ}$ C) / 20 \sim 60% / Allowance 2.0cm/s² (=2.0gal) Recommended (=2.0gal) Recommended 0.5cm/s²			20~25°C (Variation ± 1 °C) / 20~60% / Allow. 2.0cm/s² (=2.0gal) Rec. 0.5cm/s²	20~23°C (Variation ±0.5°C) / 20~60% / Allow. 1.0cm/s² (=1.0gal) Rec. 0.5cm/s²		
Required power source					AC100V±5% / 14A					
Air: Pressure 0.5MPa~1.0MPa Flow rate	100 L/min(ANR)	150 L/m	in(ANR)	250 L/min(ANR)	450 L/	min(ANR)	100 L/min(ANR)	150 L/min(ANR)	200 L/min(ANR)	350 L/min(ANR)
Standard accessories				Top ceramic stylus R500 μm, Top diamond stylus R2D60,	Probe, Standard sphere for calibration, Printer		Top ceramic stylus R500 μm Top diamond stylus R2D60 Side ruby stylus Φ2 mm Probe, Standard sphere for calibration,Printer	Top ceramic stylus R500 μ m, Top diamond stylus R2D60 Probe, Standard sphere for calibration, Printer		

*1: Wind from air conditioners should not directly blow onto the equipment

*2: • This product is categorized as a product (or technology) that qualifies as a regulated cargo as specified by the Foreign Exchange and Foreign Trade Act.
• To export or transfer abroad applicable products (or technology), you must gain permission for export in advance from the Japanese government.

Freeform / Multipule segments formula

Supports CAD based design fomula Supports future manufacturing with Nano-precision for automotive parts and complex shaped parts.

Measured objects Headlight • LiDER lens

AR/VR

- HUD · Projector, and other

Measurement examples

CAD data linkage using CAD/CAM software



Multipule

segment work

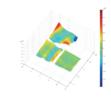


3DCAD data









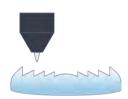
Generating design formulas and NC (STEP/IGES, and other) path using CAD data

High-precision error map positioned relating CAD data

*Generates points cloud from CAD byusing KISTEM Opt -1

Diffractive lens measurement

Enabling diffractive lens measurement and evaluation

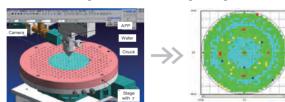




Wafer lens measurement

Enabling wafer lens measurement and evaluation

Measured on an alignment mark basis using a recognition camera



Specifications

	Software Option	Details
1	Circular scanning measurement function	Adds circumferential scanning NC paths for measured objects with a hole in the center.
2	Top Flat centering function	Function that enables centering of a measuring object whose center is nearly flat.
3	User-defined formula function	Function to evaluated by user created formula.
4	Aspherical coefficients fitting function	Function to fit aspherical coefficients based on measured data.
5	Diamond stylus correction function	Function to correct stylus tip shape based on standard sphere measured data.
6	Point cloud data design formula creation function	Function to generate a spline curved formula based on points cloud converted from CAD data(provided by the customer)
7	One million data points sampling, captureing 2000 points per second function	Function to expand the number of measurement points and to increase the speed of capturing data points
8	Waveguide software (offline)	Function to evaluate the dimensions of the shape of an object based on the measured data
9	Decenter and tilt evaluation software (offline)	Function to evaluate decenter and tilt of lens front and back using the jig installed 3 sphere.
10	Automatic Measurement Software	Function to create measurtement procedure program and to execute procedures automatically.
11	Wafer lens measurement software	Function to measure and evaluate wafer lenses in combination with mechanical option[2]

	Mechanics Option	Details				
1	Auto Tilt Stage (2 Axis, 3 Axis)	Mechanism that automatically corrects the tilt of a measuring object based on its measured data.				
2	Wafer Chuck & Stage	Adding an air chucking stage and recognition camera for wafer lens measurement				
3	Decenter and Tilt measuring Jig(various types)	Jig used for decenter and tilt measurement (used in combination with option software[9])				

UA3P-400T

Top and side surface measurement

Achieved the scanning measurement of the vertical sides of a lens or a lens barrel with an accuracy of 50 nm.

Positional deviation on the order of 100 nm can be measured in combination with optical surface data.



Measurement examples

Top surface measurement

Mold measurement

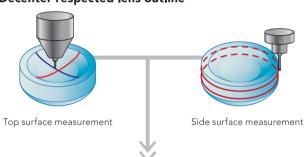


Concave shaped mold

Shape error evaluation

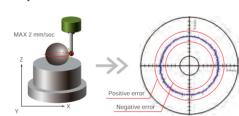
Top + Side surface

Decenter respected lens outline

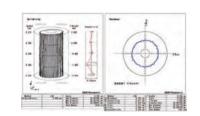


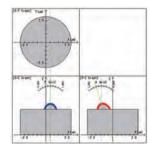
Side surface measurement

Sphere measurement



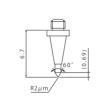
Pin gauge measurement





* UA3P-400T corresponds to product related to weapons of mass destruction

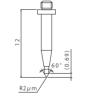
Stylus



PED-16100112



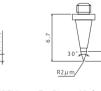
Side Ruby Stylus φ1mm



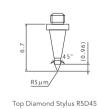
(L=12mm)PED-16100116

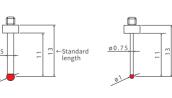


PED-1610M106

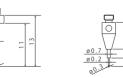


PED-1610M052





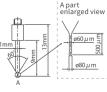
Side Ruby Stylus φ2mm PED-1630M020

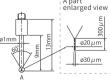


Side Ruby Stylus φ300μm



Side Ceramic Stylus φ1mm





Side Carbide Stylus φ80μm

Side Carbide Stylus φ30μm PED-1630M025